4/16/2014

RELIABILITY MONITOR REPORT
FOR

X3 0.6µm Silicon Gate CMOS (C6)

MAXIM INTEGRATED

160 RIO ROBLES
SAN JOSE, CA 95134

This Report was prepared by
MAXIM INTEGRATED Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX5048BAUT

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 9302 QUANTITY: 48 FAILS: 0 FITS: 12.3

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2013 and 3/31/2014 .

Process Information:

Process Description: X3 0.6µm Silicon Gate CMOS (C6)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1344	MAX5048BAUT+	135°C	1000 HRS	48	0	SH71HA182QA
				Total:		**0**	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1344	MAX5048BAUT+	150°C	1000 HRS	80	0	SH71HA182QA
				Total:		**0**	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1344	MAX5048BAUT+	-65C TO 150C	1000 CYS	80	0	SH71HA182QA
				Total:		**0**	

TEMPERATURE HUMIDITY BIAS

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
BIASED MOISTURE	1344	MAX5048BAUT+	130C, 85% R.H.	100 HRS	79	0	SH71HA182QA
				Total:		**0**	

FAILURE RATE: MTTF (YRS): 9302 QUANTITY: 48 FAILS: 0 FITS: 12.3